

## EAST SEARCH

7/2/2007

L#	Hits	Search String	Databases
S1	494501	(chemical or petrochemical or manufacturing) near2 process\$2	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S2	573	((chemical or petrochemical or manufacturing) near2 process\$2) with (process near2 model\$	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S3	785	((chemical or petrochemical or manufacturing) near2 process\$2) same (process near2 model\$	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S4	785	S2 or S3	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S5	73	S4 and (integrated near2 model\$3)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S6	5	S4 and (symbolic near2 (model\$3 or language))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S17	85	S4 and (process with environment with model\$3)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S18	0	S4 and ((log or logging) with (assumption or (model near2 transformation)))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S7	20	S4 and (symbolic near2 (manipulation or representation or description))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S22	1	S4 and ((rate near2 change) with (mass near2 (vapor or liquid)))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S8	2	S4 and (ancestor near2 model\$3)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S23	52	S4 and (rate near2 change)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S24	10	S4 and (energy near2 (vapor or liquid))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S25	6	S4 and ((pressure or thermal) near2 equilibrium)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S27	4	S4 and ("equal pressure" or "gas law" or "volume correlation")	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S29	207	S9 or S13	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S30	153	S28 and S29	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S9	132	S4 and ((specific or environment) near2 model\$3)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S31	306	S28 or S30	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S32	20	S31 and (S6 or S7)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S33	2	S31 and S8	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S34	3	S4 and (formal near2 language)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S38	9	S4 and (model near2 transformation)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S40	2	S31 and S20	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S41	3	S31 and S21	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S45	4	S31 and S27	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S10	33	S4 and ((formal near2 language) or (equation near2 based))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S11	8	S4 and (Mathematica or Axiom or MAPLE or ADIFOR)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S12	35	S4 and (generic near2 (model\$3 or component))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S13	142	S4 and (model\$3 with (assumption or environment))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S14	2	S4 and (component near2 specific near2 model)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S15	65	S4 and (component near2 model)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S16	9	S4 and (environment near2 independent)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S19	75	S4 and (log or logging)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S20	2	S4 and (flash near2 column)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S21	3	S4 and (parameter near2 representation)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S26	6	S4 and ((vapor or liquid) near2 (enthalpy or heat))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S28	306	S5 or S6 or S7 or S8 or S10 or S11 or S12 or S14 or S15 or S16 or S17 or S19 or S20 or S2	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S35	3	S31 and S34	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S36	8	S31 and S11	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S37	85	S31 and S17	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB

S39	7	S31 and S38	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S42	3	S4 and (mass near2 (vapor or liquid))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S44	6	S31 and S25	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S43	10	S31 and (S24 or S42)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S74	306	S71 or S73	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S46	573	((chemical or petrochemical or manufacturing) near2 process\$2) with (process near2 model\$	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S68	6	S48 and ((pressure or thermal) near2 equilibrium)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S65	1	S48 and ((rate near2 change) with (mass near2 (vapor or liquid)))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S64	3	S48 and (parameter near2 representation)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S67	10	S48 and (energy near2 (vapor or liquid))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S66	52	S48 and (rate near2 change)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S63	2	S48 and (flash near2 column)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S62	75	S48 and (log or logging)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S61	85	S48 and (process with environment with model\$3)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S60	9	S48 and (environment near2 independent)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S59	65	S48 and (component near2 model)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S58	2	S48 and (component near2 specific near2 model)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S57	142	S48 and (model\$3 with (assumption or environment))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
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S55	8	S48 and (Mathematica or Axiom or MAPLE or ADIFOR)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S54	33	S48 and ((formal near2 language) or (equation near2 based))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S53	132	S48 and ((specific or environment) near2 model\$3)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S52	2	S48 and (ancestor near2 model\$3)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S51	20	S48 and (symbolic near2 (manipulation or representation or description))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S50	5	S48 and (symbolic near2 (model\$3 or language))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S49	73	S48 and (integrated near2 model\$3)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S48	785	S46 or S47	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S47	785	((chemical or petrochemical or manufacturing) near2 process\$2) same (process near2 model\$	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S73	153	S71 and S72	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S72	207	S53 or S57	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S71	306	S49 or S50 or S51 or S52 or S54 or S55 or S56 or S58 or S59 or S60 or S61 or S62 or S63 c	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S70	4	S48 and ("equal pressure" or "gas law" or "volume correlation")	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S69	6	S48 and ((vapor or liquid) near2 (enthalpy or heat))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S88	106	S77 and (process with environment with model\$3)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S91	4	S77 and (parameter near2 representation)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S94	11	S77 and (energy near2 (vapor or liquid))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S95	7	S77 and ((pressure or thermal) near2 equilibrium)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S97	4	S77 and ("equal pressure" or "gas law" or "volume correlation")	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S98	360	S78 or S79 or S80 or S81 or S82 or S83 or S84 or S85 or S86 or S87 or S88 or S89 or S90 c	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S102	33	S99 and S101	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S103	47	S100 or S102	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S80	21	S77 and (symbolic near2 (manipulation or representation or description))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S79	6	S77 and (symbolic near2 (model\$3 or language))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S84	40	S77 and (generic near2 (model\$3 or component))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S81	2	S77 and (ancestor near2 model\$3)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S77	915	S75 or S76	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S76	915	((chemical or petrochemical or manufacturing) near2 process\$2) same (process near2 model\$	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB

S78	83	S77 and (integrated near2 model\$3)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S75	665	((chemical or petrochemical or manufacturing) near2 process\$2) with (process near2 model\$3)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S86	74	S77 and (component near2 model)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S87	14	S77 and (environment near2 independent)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S89	88	S77 and (log or logging)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S90	2	S77 and (flash near2 column)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S92	1	S77 and ((rate near2 change) with (mass near2 (vapor or liquid)))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S93	61	S77 and ((rate near2 change)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S96	11	S77 and ((vapor or liquid) near2 (enthalpy or heat))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S101	120	S77 and (specific near2 model\$3)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S99	100	S77 and ((generic or general or universal) near2 model\$3)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S82	41	S77 and ((formal near2 language) or (equation near2 based))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S100	22	S77 and (model\$3 with assumption)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S85	2	S77 and (component near2 specific near2 model)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S83	8	S77 and (Mathematica or Axiom or MAPLE or ADIFOR)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
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### Results of search set \$91:

Document Kind	Codes	Title	Issue Date	Current OR	Abstract
US	20060195213	A1 Method of operating an advanced process controller by dynamically adapting hierarchy levels	20060831	700/108	
US	20060190913	A1 Method and apparatus for identifying a manufacturing problem area in a layout using a graphic	20060824	716/19	
US	20060190223	A1 SAMPLE PROBABILITY OF FAULT FUNCTION DETERMINATION USING CRITICAL DEFECT	20060824	703/2	
US	20060190222	A1 PROBABILITY OF FAULT FUNCTION DETERMINATION USING CRITICAL DEFECT SIZE	20060824	703/2	
US	20060178528	A1 Method of controlling acetic acid process	20060810	562/519	
US	20060172427	A1 Method and apparatus for retrofitting existing real time control systems for monitoring, control	20060803	436/55	
US	20060150129	A1 Stochastic analysis process optimization for integrated circuit design and manufacture	20060706	716/4	
US	20060136138	A1 Creation and maintenance of a history list in a method and apparatus for integrated modeling	20060622	702/19	
US	20060124156	A1 Carbon dioxide snow apparatus	20060615	134/99.1	
US	20060117654	A1 Bench scale apparatus to model and develop biopharmaceutical cleaning procedures	20060608	47158.1SC	
US	20060117067	A1 System and method for interactive visual representation of information content and relationships	20060601	707/104.1	
US	20060111804	A1 Multivariate control of semiconductor processes	20060525	700/110	
US	20060106757	A1 Search for similar sheet metal part models	20060518	707/2	
US	20060106485	A1 Enhanced digital process design methodology for process centric CAD systems	20060518	700/182	
US	20060103378	A1 Apparatus and method for dynamic diagnostic testing of integrated circuits	20060518	324/228	
US	20060101370	A1 METHOD FOR IMPROVING OPTICAL PROXIMITY CORRECTION	20060511	716/19	
US	20060100873	A1 CIRCUIT STATISTICAL MODELING FOR PARTIALLY CORRELATED MODEL PARAMETER	20060511	704/256.2	
US	20060074603	A1 Customer support system and method of customer support	20060406	702/188	
US	20060074599	A1 Application of abnormal event detection technology to olefins recovery trains	20060406	702/185	
US	20060074598	A1 Application of abnormal event detection technology to hydrocracking units	20060406	702/185	
US	20060073013	A1 Application of abnormal event detection technology to fluidized catalytic cracking unit	20060406	416/35	
US	20060069958	A1 Defect location identification for microdevice manufacturing and test	20060330	714/33	
US	20060069541	A1 Reuse of manufacturing process design models as part of a diagnostic system	20060330	703/22	
US	20060058898	A1 System and method for abnormal event detection in the operation of continuous industrial process	20060316	700/29	
US	20060015294	A1 Data collection and analysis system	20060119	702/183	

US 20060014394 A1	Process for low temperature, dry etching, and dry planarization of copper	20060119 438/710
US 20050272640 A1	Method and apparatus for glucose control and insulin dosing for diabetics	20051208 514/3
US 20050270199 A1	Method for designing mixed signal integrated circuits and configurable synchronous digital nc	20051208 341/120
US 20050268256 A1	Modeling resolution enhancement processes in integrated circuit fabrication	20051201 716/4
US 20050267723 A1	Physicochemical process modelling system	20051201 703/11
US 20050261888 A1	Time dependent process parameters for integrated process and product engineering	20051124 703/22
US 20050261887 A1	Time dependent process parameters and engineering change number conflict report	20051124 703/22
US 20050261791 A1	Interfaces from external systems to time dependent process parameters in integrated process	20051124 700/97
US 20050235246 A1	Use of models in integrated circuit fabrication	20051020 716/21
US 20050234586 A1	Predictive modeling of machining line variation	20051020 700/159
US 20050228511 A1	Computer-implemented system and method for measuring and improving manufacturing proc.	20051013 700/28
US 20050209834 A1	Horizontally structured CAD/CAM modeling-vertical to horizontal conversion	20050922 703/2
US 20050187747 A1	Method and apparatus for improved simulation of chemical and biochemical reactions	20050825 703/11
US 20050187746 A1	Method and apparatus for improved modeling of chemical and biochemical reactions	20050825 703/11
US 20050187745 A1	Method and apparatus facilitating communication with a simulation environment	20050825 703/11
US 20050187717 A1	Method and apparatus for integrated modeling, simulation and analysis of chemical and bioc	20050825 702/19
US 20050187643 A1	Parametric universal nonlinear dynamics approximator and use	20050825 700/29
US 20050181342 A1	Medical training simulator including contact-less sensors	20050818 434/262
US 20050159934 A1	Integrated modeling through symbolic manipulation	20050721 703/2
US 20050154477 A1	Kiln control and upset recovery using a model predictive control in series with forward chainin	20050714 700/37
US 20050132306 A1	Characterization and reduction of variation for integrated circuits	20050616 716/1
US 20050120010 A1	System and method for determining costs within an enterprise	20050602 707/3
US 20050065767 A1	Closed loop integration of digital models of in silico systems and experimental procedures	20050324 703/22
US 20050065626 A1	Material reseruation distribution system and method	20050324 700/97
US 20050060584 A1	Trusted infrastructure support systems, methods and techniques for secure electronic comm	20050317 726/4
US 20050045029 A1	Selective separation of fluid compounds utilizing a membrane separation process	20050303 95/46
US 20050037522 A1	Dummy fill for integrated circuits	20050217 438/8
US 20050010319 A1	System and method for validating and visualizing APC assisted semiconductor manufacturing	20050113 700/121
US 20050004687 A1	Apparatus and method of controlling multi-input-single-output systems	20050106 700/44
US 20040256230 A1	Microfluidic devices for transverse electrophoresis and isoelectric focusing	20041223 204/450
US 20040230411 A1	Apparatus and methods for predicting properties of processed material	20041118 703/6
US 20040220691 A1	Method and apparatus for constructing crowns, bridges and implants for dental use	20041104 700/98
US 20040220689 A1	Sensor placement and control design for distributed parameter systems	20041104 700/97
US 20040210429 A1	Apparatus and methods for performing process simulation using a hybrid model	20041021 703/9
US 20040182786 A1	Purification of fluid compounds utilizing a distillation - membrane separation process	20040923 210/640
US 20040167763 A1	Information processing method for evaluating biochemical pathway models using clinical date	20040826 703/11
US 20040154965 A1	Wet and dry weather water flows disinfection system	20040812 210/85
US 20040153296 A1	Horizontally structured CAD/CAM coordinate system	20040805 703/2
US 20040153202 A1	Horizontally structured manufacturing process modeling: across file feature operability	20040805 700/182
US 20040153201 A1	Horizontally structured CAD/CAM coordinate system for manufacturing design	20040805 700/182
US 20040153200 A1	Horizontally structured manufacturing process modeling: exterior linked representational emb	20040805 700/182
US 20040153197 A1	Modeling an abrasive process to achieve controlled material removal	20040805 700/164
US 20040148047 A1	Hierarchical methodology for productivity measurement and improvement of productions syst	20040729 700/100
US 20040139419 A1	Minimization of microelectronic interconnect thickness variations	20040715 716/20
US 20040130276 A1	System and method of applying adaptive control to the control of particle accelerators with va	20040708 315/501
US 20040128003 A1	SYSTEM AND METHOD FOR MODEL BASED CONTROL OF A NEURAL NETWORK	20040701 700/31
US 20040128002 A1	SYSTEM AND METHOD FOR MODEL BASED CONTROL OF A CHEMICAL PROCESS	20040701 700/31
US 20040123129 A1	Trusted infrastructure support systems, methods and techniques for secure electronic comm	20040624 713/193

US 20040121495 A1	Dynamic adaptive sampling rate for model prediction	20040624 438/14
US 20040117040 A1	System and method of adaptive control of processes with varying dynamics	20040617 700/29
US 20040102935 A1	Method for regulating a property of a product derived from a chemical transformation	20040527 703/2
US 20040099213 A1	Spatially programmable microelectronics process equipment using segmented gas injection s	20040527 118/15
US 20040093107 A1	Probability constrained optimization for electrical fabrication control	20040513 700/108
US 20040088149 A1	Method and apparatus for performing OPC using model curvature	20040506 703/13
US 20040088065 A1	Cooperative smart items	20040506 700/95
US 20040083452 A1	Method and system for predicting multi-variable outcomes	20040429 717/109
US 20040083028 A1	Process control using on-line instrumentation and process models	20040429 700/269
US 20040076944 A1	Supervised learning in the presence of null data	20040422 434/433
US 20040068342 A1	Method of designing and manufacturing rubber process tooling using an interface to a CAD/C	20040408 700/182
US 20040068332 A1	Stochastic modeling of spatial distributed sequences	20040408 700/51
US 20040034555 A1	Hierarchical methodology for productivity measurement and improvement of complex product	20040219 705/7
US 20040034517 A1	DEVICE MODELING FOR PROXIMITY EFFECTS	20040219 703/14
US 20040028253 A1	Detoxification of solid freeform fabrication materials	20040212 381/322
US 20040015335 A1	Method, system and medium for controlling manufacturing process using adaptive models ba	20040122 703/2
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L1	377	((chemical or petrochemical or manufacturing) near2 process\$2) same (process near2 model\$3 or language))	US-PGPUB
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L4	7	1 and (symbolic near2 (manipulation or representation or description))	US-PGPUB
L5	4	1 and (Mathematica or Axiom or MAPLE or ADIFOR)	US-PGPUB
L6	23	1 and (generic near2 (model\$3 or component))	US-PGPUB
L7	80	1 and (specific near2 model\$3)	US-PGPUB
L8	40	1 and (component near2 model)	US-PGPUB
L9	23	1 and (generic near2 (model\$3))	US-PGPUB
L10	17	7 and 8	US-PGPUB
L11	95	3 or 4 or 5 or 6 or 7 or 9 or 10	US-PGPUB
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L14	1	11 and (symbolic.CLM.)	US-PGPUB
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L16	1	11 and (Axiom.CLM.)	US-PGPUB
L17	1	11 and (MAPLE.CLM.)	US-PGPUB
L18	1	11 and (ADIFOR.CLM.)	US-PGPUB
L19	25	12 or 13 or 14 or 15 or 16 or 17 or 18	US-PGPUB

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US	20060069958	A1 Defect location identification for microdevice manufacturing and test	20060330	714/33	
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US	20060058898	A1 System and method for abnormal event detection in the operation of continuous industrial process	20060316	700/29	
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... from the group consisting of Mathematica, **Axiom**, MAPLE and ... of claim 1 wherein the generic model comprises a ... of claim 1 wherein the specific model comprises a ...

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